



SLOVENSKI STANDARD
SIST-TS CEN ISO/TS 17200:2015
01-julij-2015

Nanotehnologija - Nanodelci v obliki prahu - Karakteristike in mere (ISO/TS 17200:2013)

Nanotechnology - Nanoparticles in powder form - Characteristics and measurements (ISO/TS 17200:2013)

Nanotechnologien - Nanopartikel in Pulverform - Eigenschaften und Messung (ISO/TS 17200:2013)

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Nanotechnologies - Nanoparticules sous forme de poudre - Caractéristiques et mesures (ISO/TS 17200:2013)

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Ta slovenski standard je istoveten z: CEN ISO/TS 17200:2015

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07.120

Nanotehnologije

Nanotechnologies

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en

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TECHNICAL SPECIFICATION
SPÉCIFICATION TECHNIQUE
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CEN ISO/TS 17200

May 2015

ICS 07.030

English Version

**Nanotechnology - Nanoparticles in powder form - Characteristics
and measurements (ISO/TS 17200:2013)**

Nanotechnologies - Nanoparticules sous forme de poudre -
Caractéristiques et mesures (ISO/TS 17200:2013)

Nanotechnologien - Nanopartikel in Pulverform -
Eigenschaften und Messung (ISO/TS 17200:2013)

This Technical Specification (CEN/TS) was approved by CEN on 16 May 2015 for provisional application.

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Contents

	Page
Foreword.....	3

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[SIST-TS CEN ISO/TS 17200:2015](https://standards.iteh.ai/catalog/standards/sist/a23852c4-8184-43ca-8524-156d26ab62fe/sist-ts-cen-iso-ts-17200-2015)
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Foreword

The text of ISO/TS 17200:2013 has been prepared by Technical Committee ISO/TC 229 “Nanotechnologies” of the International Organization for Standardization (ISO) and has been taken over as CEN ISO/TS 17200:2015 by Technical Committee CEN/TC 352 “Nanotechnologies” the secretariat of which is held by AFNOR.

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Endorsement notice

The text of ISO/TS 17200:2013 has been approved by CEN as CEN ISO/TS 17200:2015 without any modification.

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**Nanotechnology — Nanoparticles in
powder form — Characteristics and
measurements**

*Nanotechnologies — Nanoparticules sous forme de poudre —
Caractéristiques et mesures*

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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Fundamental characteristics with corresponding measurement methods	2
5 Sample preparation	2
6 Measurement methods	3
6.1 Chemical composition.....	3
6.2 Specific surface area by BET method.....	4
6.3 Crystal structure by XRD method.....	4
6.4 Average crystallite size by XRD (Scherrer formula) method.....	4
6.5 Average and standard deviation of the measured primary particle sizes by TEM method.....	4
7 Test report	4
Annex A (informative) Applicability of this Technical Specification	6
Bibliography	7

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